

4-Mbit (512 K × 8) Static RAM

Features

- Higher speed up to 55 ns
- Wide voltage range: 2.2 V to 3.6 V and 4.5 V to 5.5 V
- Ultra low standby power
 - □ Typical standby current: 1 µA
 - □ Maximum standby current: 7 µA
- Ultra low active power
 - □ Typical active current: 2 mA at f = 1 MHz
- Easy memory expansion with CE and OE features
- Automatic power-down when deselected
- Complementary metal oxide semiconductor (CMOS) for optimum speed and power
- Available in Pb-free 32-pin shrunk thin small outline package (STSOP) package

Functional Description

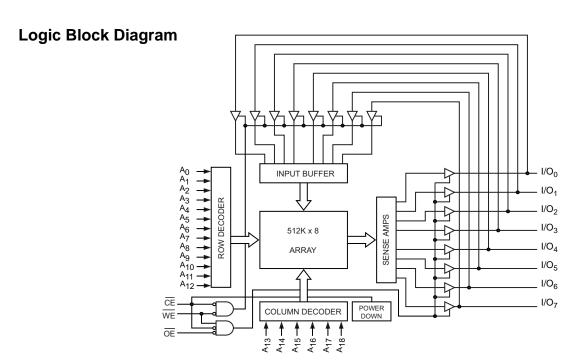
The CY62148ESL is a high performance CMOS static RAM organized as 512 K words by 8-bits. This device features advanced circuit design to provide ultra low active current. This is ideal for providing More Battery Life $^{\text{TM}}$ (MoBL $^{\text{®}}$) in portable applications. The device also has an automatic power-down feature that significantly reduces power consumption. Placing the device in standby mode reduces power consumption by more than 99 percent when deselected ($\overline{\text{CE}}$ HIGH). The eight input and output pins (I/O₀ through I/O₇) are placed in a high impedance state when the device is deselected ($\overline{\text{CE}}$ HIGH), the outputs are disabled ($\overline{\text{OE}}$ HIGH), or during a write operation ($\overline{\text{CE}}$ LOW and $\overline{\text{WE}}$ LOW).

 $\overline{\text{To}}$ write to the device, take Chip Enable $(\overline{\text{CE}})$ and Write Enable $(\overline{\text{WE}})$ inputs LOW. Data on the eight I/O pins $(\text{I/O}_0$ through I/O₇) is then written into the location specified on the address pins $(A_0$ through $A_{18})$.

To read from the device, take Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) LOW while forcing Write Enable (\overline{WE}) HIGH. Under these conditions, the contents of the memory location specified by the address pins appear on the I/O pins.

The CY62148ESL device is suitable for interfacing with processors that have TTL I/P levels. It is not suitable for processors that require CMOS I/P levels. Please see Electrical Characteristics on page 4 for more details and suggested alternatives.

For a complete list of related resources, click here.



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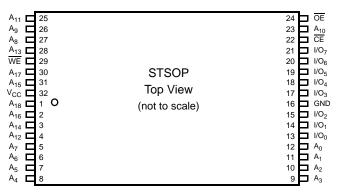
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Pin Configuration

Figure 1. 32-pin STSOP (Top View) pinout



Product Portfolio

	t Range V _{CC} Range (V) [1]					Power D	Dissipatio	on	
Product			Speed	Operating I _{CC} , (mA)		4)	Standby, I _{SB2} (µA		
Troduct	Range	ACC Ivalide (A)	(ns)	f = 1 MHz		MHz f = f _{max}		Otaliday, ISB2 (μΑ)	
				Typ [2]	Max	Typ [2]	Max	Typ [2]	Max
CY62148ESL	Industrial / Automotive-A	2.2 V to 3.6 V and 4.5 V to 5.5 V	55	2	2.5	15	20	1	7

Notes

Data sheet specifications are not guaranteed for V_{CC} in the range of 3.6 V to 4.5 V.
 Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.



Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Storage temperature-65 °C to +150 °C Ambient temperature with power applied ... 55 °C to +125 °C Supply voltage to ground potential-0.5 V to 6.0 V DC voltage applied to outputs in high Z state $^{[3,\ 4]}$ -0.5 V to 6.0 V DC input voltage [3, 4]-0.5 V to 6.0 V

Output current into outputs (low)	20 mA
Static discharge voltage (MIL-STD-883, Method 3015)	> 2001 V
Latch-up current	> 200 mA

Operating Range

Device	Range	Ambient Temperature	V cc ^[5]
CY62148ESL	Industrial / Automotive-A		2.2 V to 3.6 V, and 4.5 V to 5.5 V

Electrical Characteristics

Over the operating range

Donomoton	Description	Took Conditions	55 ns (Inc	lustrial/Auto	omotive-A)	I Im!4
Parameter	Description	Test Conditions	Min	Typ ^[6]	Max	Unit
V _{OH}	Output HIGH voltage	$2.2 \le V_{CC} \le 2.7$ $I_{OH} = -0.1 \text{ mA}$	2.0	_	_	V
		$2.7 \le V_{CC} \le 3.6$ $I_{OH} = -1.0 \text{ mA}$	2.4	_	_	
		$4.5 \le V_{CC} \le 5.5$ $I_{OH} = -1.0 \text{ mA}$	2.4	_	_	
		$4.5 \le V_{CC} \le 5.5$ $I_{OH} = -0.1 \text{ mA}$	_	_	3.4 ^[7]	
V_{OL}	Output LOW voltage	$2.2 \le V_{CC} \le 2.7$ $I_{OL} = 0.1 \text{ mA}$	_	_	0.4	V
		$2.7 \le V_{CC} \le 3.6$ $I_{OL} = 2.1 \text{ mA}$	_	_	0.4	
		$4.5 \le V_{CC} \le 5.5$ $I_{OL} = 2.1 \text{ mA}$	_	_	0.4	
V _{IH}	Input HIGH voltage	2.2 ≤ V _{CC} ≤ 2.7	1.8	_	V _{CC} + 0.3	V
		2.7 ≤ V _{CC} ≤ 3.6	2.2	_	V _{CC} + 0.3	
		4.5 ≤ V _{CC} ≤ 5.5	2.2	_	V _{CC} + 0.5	
V _{IL} [8]	Input LOW voltage	2.2 ≤ V _{CC} ≤ 2.7	-0.3	-	0.4	V
		2.7 ≤ V _{CC} ≤ 3.6	-0.3	_	0.6	
		4.5 ≤ V _{CC} ≤ 5.5	-0.5	_	0.6	
I _{IX}	Input leakage current	$GND \le V_{IN} \le V_{CC}$	-1	_	+1	μA
I _{OZ}	Output leakage current	$GND \le V_O \le V_{CC}$, output disabled	-1	_	+1	μA
I _{CC}	V _{CC} operating supply current	$f = f_{max} = 1/t_{RC}$ $V_{CC} = V_{CCmax}$	_	15	20	mΑ
		f = 1 MHz	_	2	2.5	
I _{SB1} ^[9]	Automatic CE power-down	$\overline{CE} \ge V_{CC} - 0.2 \text{ V},$	_	1	7	μA
	current – CMOS inputs	$\begin{split} &V_{IN} \geq V_{CC} - 0.2 \text{ V or } V_{IN} \leq 0.2 \text{ V,} \\ &f = f_{max} \text{ (address and data only),} \\ &f = 0 \text{ (OE and } \overline{WE}), V_{CC} = V_{CC(max)} \end{split}$	_			
I _{SB2} ^[9]	Automatic CE power-down	$\overline{CE} \ge V_{CC} - 0.2 \text{ V},$	_	1	7	μA
	current – CMOS inputs	$V_{IN} \ge V_{CC} - 0.2 \text{ V or } V_{IN} \le 0.2 \text{ V},$ $f = 0, V_{CC} = V_{CC(max)}$	_			

- 3. $V_{IL(min)} = -2.0 \text{ V}$ for pulse durations less than 20 ns.

- V_{IL(min)} = -2.0 V for pulse durations less than 20 ns.
 V_{IH(max)} = V_{CC} + 0.75 V for pulse durations less than 20 ns.
 V_{IH(max)} = V_{CC} + 0.75 V for pulse durations less than 20 ns.
 Full device AC operation assumes a minimum of 100 µs ramp time from 0 to V_{CC(min)} and 200 µs wait time after V_{CC} stabilization.
 Typical values are included for reference and are not guaranteed or tested. Typical values are measured at V_{CC} = V_{CC(typ)}, T_A = 25 °C.
 Please note that the maximum VOH limit does not exceed minimum CMOS VIH of 3.5 V. If you are interfacing this SRAM with 5 V legacy processors that require a minimum VIH of 3.5 V, please refer to Application Note AN6081 for technical details and options you may consider
 Under DC conditions the device meets a V_{IL} of 0.8 V (for V_{CC} range of 2.7 V to 3.6 V and 4.5 V to 5.5 V) and 0.6 V (for V_{CC} range of 2.2 V to 2.7 V). However, in dynamic conditions Input LOW voltage applied to the device must not be higher than 0.6 V and 0.4 V for the above ranges.
 Chip enable (CE) must be HIGH at CMOS level to meet the loss / loss spec. Other inputs can be left floating.
- 9. Chip enable (CE) must be HIGH at CMOS level to meet the I_{SB1} / I_{SB2} / I_{CCDR} spec. Other inputs can be left floating.



Capacitance

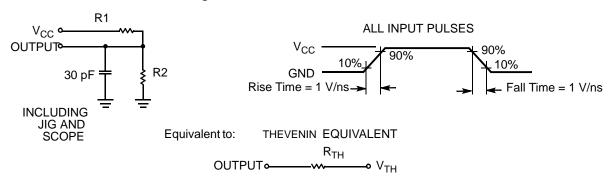
Parameter [10]	Description	Description Test Conditions		Unit
C _{IN}	Input capacitance	$T_A = 25$ °C, $f = 1$ MHz, $V_{CC} = V_{CC(Typ)}$	10	pF
C _{OUT}	Output capacitance		10	pF

Thermal Resistance

Parameter [10]	Description	Test Conditions	32-pin STSOP	Unit
$\Theta_{\sf JA}$	Thermal resistance (junction to ambient)	Still air, soldered on a 3×4.5 inch, two-layer printed circuit board	49.02	°C/W
- 30	Thermal resistance (junction to case)		14.07	°C/W

AC Test Loads and Waveforms

Figure 2. AC Test Loads and Waveforms



Parameter	2.5 V	3.0 V	5.0 V	Unit
R1	16667	1103	1800	Ω
R2	15385	1554	990	Ω
R _{TH}	8000	645	639	Ω
V _{TH}	1.20	1.75	1.77	V

Note

 $^{10. \, \}text{Tested initially and after any design or process changes that may affect these parameters}.$



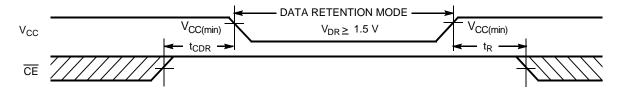
Data Retention Characteristics

Over the operating range

Parameter	Description	Conditions	Min	Тур [11]	Max	Unit
V_{DR}	V _{CC} for data retention		1.5	_	_	V
I _{CCDR} [12]	Data retention current	$\overline{CE} \ge V_{CC} - 0.2 \text{ V,} \\ V_{IN} \ge V_{CC} - 0.2 \text{ V or} \\ V_{IN} \le 0.2 \text{ V,} \\ V_{CC} = 1.5 \text{ V}$	_	1	7	μА
t _{CDR}	Chip deselect to data retention time		0	-	_	ns
t _R ^[13]	Operation recovery time		55	_	_	ns

Data Retention Waveform

Figure 3. Data Retention Waveform



^{11.} Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at $V_{CC} = V_{CC(typ)}$, $T_A = 25$ °C. 12. Chip enable (\overline{CE}) must be HIGH at CMOS level to meet the $I_{SB1} / I_{SB2} / I_{CCDR}$ spec. Other inputs can be left floating. 13. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \ge 100 \, \mu s$ or stable at $V_{CC(min)} \ge 100 \, \mu s$.



Switching Characteristics

Over the operating range

Parameter [14, 15]	Description		55 ns (Industrial / Automotive-A)	
	•	Min	Max	
Read Cycle				•
t _{RC}	Read cycle time	55	_	ns
t _{AA}	Address to data valid	_	55	ns
t _{OHA}	Data hold from address change	10	_	ns
t _{ACE}	CE LOW to data valid	_	55	ns
t _{DOE}	OE LOW to data valid	_	25	ns
t _{LZOE}	OE LOW to low Z [16]	5	_	ns
t _{HZOE}	OE HIGH to high Z [16, 17]	_	20	ns
t _{LZCE}	CE LOW to low Z [16]	10	_	ns
t _{HZCE}	CE HIGH to high Z [16, 17]	_	20	ns
t _{PU}	CE LOW to power-up	0	_	ns
t _{PD}	CE HIGH to power-up	_	55	ns
Write Cycle [18, 1	9]			•
t _{WC}	Write cycle time	55	_	ns
t _{SCE}	CE LOW to write end	40	_	ns
t _{AW}	Address setup to write end	40	_	ns
t _{HA}	Address hold from write end	0	_	ns
t _{SA}	Address setup to write start	0	_	ns
t _{PWE}	WE pulse width	40	_	ns
t _{SD}	Data setup to write end	25	_	ns
t _{HD}	Data hold from write end	0	_	ns
t _{HZWE}	WE LOW to high Z [16, 17]	-	20	ns
t _{LZWE}	WE HIGH to low Z ^[16]	10	_	ns

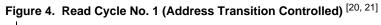
Notes

^{14.} In an earlier revision of this device, under a specific application condition, READ and WRITE operations were limited to switching of the chip enable signal as described in the Application Note AN66311. However, the issue has been fixed and in production now, and hence, this Application Notes is no longer applicable. It is available for download on our website as it contains information on the date code of the parts, beyond which the fix has been in production.

^{15.} Test conditions for all parameters other than tri-state parameters assume signal transition time of 3 ns or less (1 V/ns), timing reference levels of V_{CC(typ)}/2, input pulse levels of 0 to V_{CC(typ)}, and output loading of the specified l_{QL}/l_{OH} as shown in Figure 2 on page 5.
16. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZCE}, and t_{HZWE} for any device.
17. t_{HZCE}, t_{HZCE}, and t_{HZWE} transitions are measured when the output enter a high impedance state.
18. The internal write time of the memory is defined by the overlap of WE, CE = V_{IL}. All signals must be ACTIVE to initiate a write and any of these signals can terminate a write by going INACTIVE. The data input setup and hold timing must be referenced to the edge of the signal that terminates the write.
19. The minimum write cycle pulse width for Write Cycle No. 3 (WE Controlled, OE LOW) should be equal to the sum of t_{SD} and t_{HZWE}.



Switching Waveforms



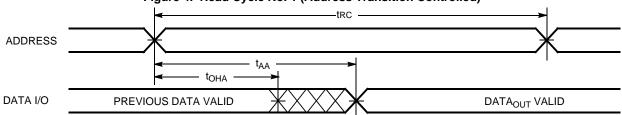
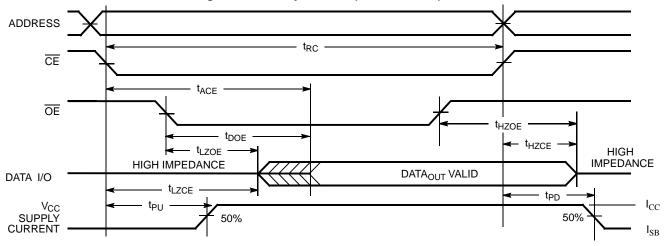


Figure 5. Read Cycle No. 2 (OE Controlled) [21, 22]



- Device is continuously selected. OE, CE = V_{IL}.
 WE is HIGH for read cycles.
 Address valid before or similar to CE transition LOW.
- 23. Data I/O is high impedance if $\overline{OE} = V_{IH}$.

 24. If \overline{CE} goes HIGH simultaneously with \overline{WE} HIGH, the output remains in high impedance state.

 25. During this period, the I/Os are in output state. Do not apply input signals.



Switching Waveforms (continued)

Figure 6. Write Cycle No. 1 (CE Controlled) [26, 27]

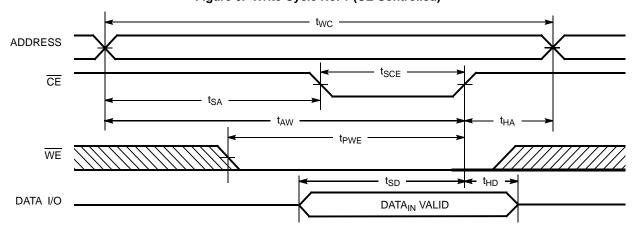
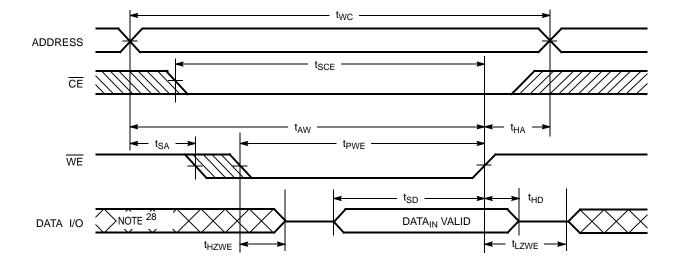


Figure 7. Write Cycle No. 2 (WE Controlled) [27]



Notes

^{26.} Data I/O is high impedance if $\overline{\text{OE}} = \text{V}_{\text{IH}}$.

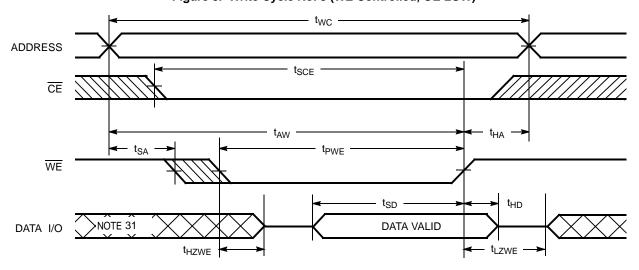
27. If $\overline{\text{CE}}$ goes HIGH simultaneously with $\overline{\text{WE}}$ HIGH, the output remains in high impedance state.

28. During this period, the I/Os are in output state. Do not apply input signals.



Switching Waveforms (continued)

Figure 8. Write Cycle No. 3 (WE Controlled, $\overline{\text{OE}}$ LOW) [29, 30]



^{29.} If $\overline{\text{CE}}$ goes HIGH simultaneously with $\overline{\text{WE}}$ HIGH, the output remains in high impedance state.

^{30.} The minimum write cycle pulse width should be equal to the sum of t_{SD} and t_{HZWE} -31. During this period, the I/Os are in output state. Do not apply input signals.



Truth Table

CE	WE	OE	I/O	Mode	Power
H ^[32]	Х	Х	High Z	Deselect/power-down	Standby (I _{SB})
L	Н	L	Data out	Read	Active (I _{CC})
L	Н	Н	High Z	Output disabled	Active (I _{CC})
L	L	Х	Data in	Write	Active (I _{CC})



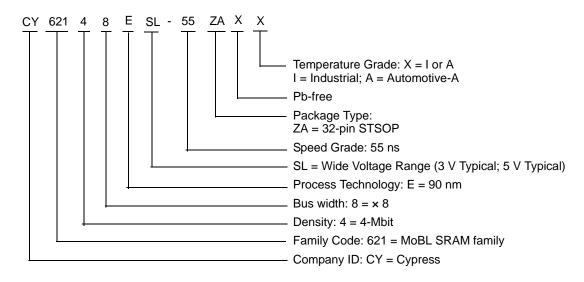
Ordering Information

Table 1 lists the CY62148ESL MoBL[®] key package features and ordering codes. The table contains only the parts that are currently available. If you do not see what you are looking for, contact your local sales representative. For more information, visit the Cypress website at www.cypress.com/products.

Table 1. Key features and Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
55	CY62148ESL-55ZAXI	51-85094	32-pin STSOP (Pb-free)	Industrial
	CY62148ESL-55ZAXA	51-85094	32-pin STSOP (Pb-free)	Automotive-A

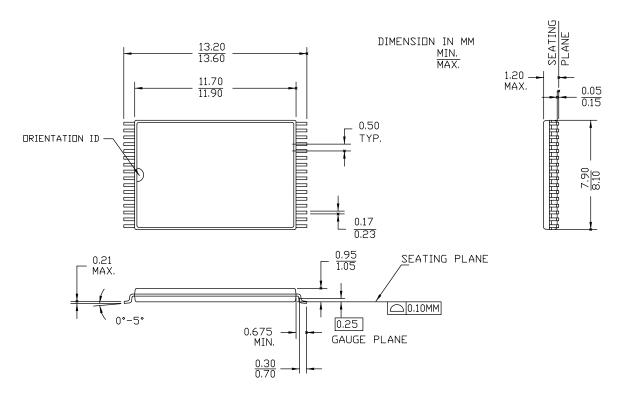
Ordering Code Definitions





Package Diagram

Figure 9. 32-pin STSOP (8 \times 13.4 \times 1.2 mm) ZA32 Package Outline, 51-85094



51-85094 *G



Acronyms

Acronym	Description			
BHE	Byte High Enable			
BLE	Byte Low Enable			
CE	Chip Enable			
CMOS	Complementary Metal Oxide Semiconductor			
I/O	Input/Output			
OE	Output Enable			
SRAM	Static Random Access Memory			
TSOP	Thin Small Outline Package			
WE	Write Enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure				
°C	degree Celsius				
MHz	megahertz				
μΑ	microampere				
mA	milliampere				
ns	nanosecond				
Ω	ohm				
pF	picofarad				
V	volt				
W	watt				



Document History Page

	Title: CY621 Number: 00		3L [®] , 4-Mbit (512	2 K × 8) Static RAM	
Rev.	ECN	Orig. of Change	Submission Date	Description of Change	
**	2612938	VKN / PYRS	01/21/09	New data sheet.	
*A	2800124	VKN	11/06/2009	Updated Product Portfolio (Included Automotive-A information). Updated Operating Range (Included Automotive-A information). Updated Ordering Information (Updated part numbers (Included Automotive-A information)).	
*B	2947039	VKN	06/10/2010	Updated Electrical Characteristics (Added Note 9 and referred the same note in I _{SB2} parameter). Updated Truth Table (Added Note 32 and referred the same note in CE column). Updated Package Diagram.	
*C	3006318	AJU	08/23/2010	Updated Electrical Characteristics (Updated Note 9 and referred the same note in I _{SB1} parameter). Updated Data Retention Characteristics (Added Note 12 and referred the same note in I _{CCDR} parameter). Added Ordering Code Definitions. Added Acronyms and Units of Measure. Updated in new template.	
*D	3296704	RAME	06/29/2011	Updated Functional Description (Removed "For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines."). Updated Ordering Code Definitions. Updated Package Diagram to latest revision.	
*E	3515577	TAVA	02/03/2012	Updated Switching Waveforms.	
*F	3548240	TAVA	03/12/2012	Updated Electrical Characteristics (Updated Note 8 (Removed "Refer t AN13470 for details.").	
*G	3897076	MEMJ	02/06/2013	Updated Switching Waveforms: Removed figure "Write Cycle No. 1 (WE Controlled, OE HIGH During Write)". Updated title of Figure 7.	
*H	4039358	MEMJ	07/01/2013	Updated Functional Description. Updated Electrical Characteristics: Added one more Test Condition "4.5 \leq V $_{CC}$ \leq 5.5" for V $_{OH}$ parameter and added maximum value corresponding to that Test Condition. Added Note 7 and referred the same note in maximum value for V $_{OH}$ parameter corresponding to Test Condition "4.5 \leq V $_{CC}$ \leq 5.5". Updated to new template.	
*	4099182	VINI	08/19/2013		
*J	4779516	MEMJ	05/28/2015	Updated Functional Description: Added "For a complete list of related resources, click here." at the end. Updated AC Test Loads and Waveforms: Updated Figure 2. Updated Switching Characteristics: Added Note 19 and referred the same note in "Write Cycle". Updated Switching Waveforms: Added Figure 8. Added Figure 8. Added Note 29, 30, 31 and referred the same note in Figure 8. Updated Package Diagram: spec 51-85094 – Changed revision from *F to *G. Updated to new template.	



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